

2633
JF
2/04/03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
ATTY. DOCKET NO. 78848-33 JMc:MPP:rmk

In Patent Application of DAVID W. BOERTJES ET AL.

RECEIVED

Serial No. 10/067,910

Group Art Unit: 2633

JAN 29 2003

Filed: February 8, 2002

Examiner:

Technology Center 2600

For: METHOD OF WDM CHANNEL TAGGING AND MONITORING, AND APPARATUS

INFORMATION DISCLOSURE STATEMENT

This Information Disclosure Statement is being filed in the manner prescribed by 37 CFR 1.97(b) - (d) to satisfy the duty under 37 CFR 1.56 to disclose to the Office information, known to individuals associated with the filing and prosecution of the subject application, which is material to the examination of the application.

In accordance with 37 CFR 1.97(g) and (h), this statement is not to be construed as a representation that a search has been made or an admission that the information cited herein is, or is considered to be, material to patentability as defined in 37 CFR 1.56(b).

This information disclosure statement is being filed within three months of the filing date of a national application, within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; or before the mailing date of a first official action on the merits and therefore applicant respectfully requests consideration 37 CFR 1.97(b).

In compliance with 37 CFR 1.98(a)(1), a list of all patents, publications or other information submitted for consideration by the Office is hereby provided by way of the attached Form PTO 1449.

In compliance with 37 CFR 1.98(a)(2), also enclosed is a legible copy of:

- i) each United States and foreign patent;
- ii) each publication or that portion which caused it to be listed; and
- iii) all other information or that portion which caused it to be listed, excluding any copies of a United States patent application.

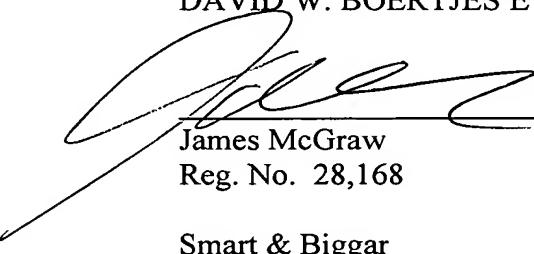
It is respectfully requested that the information be expressly considered by the Examiner and that the references be made of record and appear among the "References Cited" on any patent to issue therefrom.

The Patent Office is hereby authorized to charge any deficiency, or credit any overpayment in fees to Deposit Account Number 19-2550.

Respectfully submitted,

DAVID W. BOERTJES ET AL.

Dated: January 24, 2003

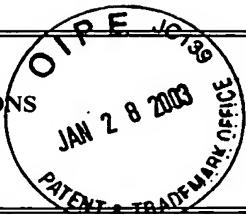


James McGraw
Reg. No. 28,168

Smart & Biggar
Box 2999, Station D
55 Metcalfe Street, Suite 900
Ottawa, Ontario
Canada K1P 5Y6
Telephone: (613) 232-2486
Fax: (613) 232-8440

Encls.: Form PTO-1449
All references listed on Form PTO-1449

Form PTO-1449 (Modified)	Atty. Docket No. 71493-949	Serial No. 10/029,282
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	JAN 28 2003 PATENT & TRADEMARK OFFICE	
	Applicant DAVID W. BOERTJES ET AL	Filing Date December 28, 2001 Group 1773



REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

RECEIVED

JAN 29 2003

Technology Center 2600

FOREIGN PATENT DOCUMENTS

OTHER ART (including Author, Title, Date, Pertinent Pages, Etc.)

	AB	Richard Habel, Kim Roberts, Alan Solheim, and James Harley, "Optical Domain Performance Monitoring", Proc. OFC2000, Vol. 2, pp. 174-175, 2000.
	AC	H. S. Chung, S.K. Shin, K.J. Park, H.G. Woo, and Y.C. Chung, "Effects of Stimulated Raman Scattering on Pilot-Tone-Based WDM Supervisory Technique", IEEE Photon. Technol. Lett., Vol. 12, No. 6, pp. 731-733, June 2000.
	AD	Saeid Seydnejad, James Harley, and Frederic Simard, "Estimation of the SRS crosstalk on pilot-tones in WDM systems using a dither transfer matrix", Proc. OFC2001, Vol. 3, pp. WDD37-1-WDD37-4, March 2001.
	AE	S. Seydnejad, F. Simard, J. Harley, "Higher Order Effects in SRS Pilot-Tones Interaction", Optical Amplifiers and Their Applications Conference (OAA'2001), Stresa, Italy, July 2001, Optical Society of America (OSA), OtuE17-1 to OtuE17-3.

EXAMINER _____ **DATE CONSIDERED** _____

EXAMINER:

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.